CLAIMS

What is claimed is:

1. A method for testing a processor design, the method comprising:

searching a file that contains test results for a lot of wafers at two or more voltage levels; and

determining an optimal operational voltage based on which of the two or more voltage levels had the least test failures.

2. The method of claim 1, wherein the searching the file comprises parsing the file.

3. The method of claim 1, wherein the searching the file comprises opening the file and parsing the file.

4. The method of claim 1, wherein the determining an optimal operational voltage comprises:

determining the number of test failures at a first voltage level;

determining the number of test failures at a second voltage level; and

determining which of the first voltage level and the second voltage level had the least test failures.

5. The method of claim 1, wherein the searching the file comprises decompressing the file.

6. A system for testing a processor design, the system comprising:

a parser module for searching a file that contains test results for a lot of wafers at two or more voltage levels;

a test failure calculation module for determining how many test failures occurred at the two or more voltage levels; and

an optimal operational voltage module for determining which of the two or more voltage levels had the least test failures.

7. The system of claim 6, wherein the parser module is configured to open the file.

8. The system of claim 6, wherein the parser module, the test failure calculation module, and the optimal operational voltage module comprise software that is executed by a processor.

9. The system of claim 6, wherein the parser module is configured to decompress the file.

10. The system of claim 6, wherein the parser module, the test failure calculation module, and the optimal operational voltage module comprise a PERL script.

11. A computer program embodied in a computer-readable medium for testing a processor design, the program comprising:

logic configured to search a file that contains test results for a lot of wafers at two or more voltage levels; and

logic configured to determine an optimal operational voltage based on which of the two or more voltage levels had the least test failures.

12. The program of claim 11, wherein the logic configured to search is further configured to decompress the file.

13. The program of claim 12, wherein the logic configured to search is further configured to parse the file.

14. The program of claim 11, wherein the logic configured to determine an optimal operational voltage comprises logic configured to:

determine the number of test failures at a first voltage level;

determine the number of test failures at a second voltage level; and

determine which of the first voltage level and the second voltage level had the least test failures.

15. A system for testing a processor design, the system comprising:

means for searching a file that contains test results for a lot of wafers at two or more voltage levels; and

means for determining an optimal operational voltage based on which of the two or more voltage levels had the least test failures.